Special Issue

Signal, Image and Video Processing

Message from the Guest Editor

An objective of this Special Issue is to present innovative developments of various aspects of signal, image, and video processing. It seeks to offer broad coverage of recent developments of signal, image, and video areas in both theory and applications. Numerous image and video applications using artificial intelligence and deep learning are emerging these days. This Special Issue covers theory, algorithms, methods, and architectures for the processing, formation, communication, and analysis of signals, images, and video in a variety of applications. Topics include but are not limited to:

- Signal/image/video representation;
- Image/video understanding;
- Image/video compression;
- Intelligent signal processing;
- Image enhancement and denoising based on deep learning;
- Depth estimation and 3D reconstruction;
- Image and video quality metrics;
- Computer vision using convolutional neural networks.

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Deadline for manuscript submissions

closed (31 August 2021)

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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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